

Bin i	d_{VV} range	Observed n_i	Expected event yield
1	0.0–0.2 mm	6	6.2 ± 1.0
2	0.2–0.4 mm	193	192.6 ± 3.9
3	0.4–0.6 mm	45	48.1 ± 3.8
4	0.6–0.8 mm	5	3.5 ± 1.4
5	0.8–1.0 mm	1	0.3 ± 0.1
6	1.0–50 mm	1	0.3 ± 0.1